

Search Notes

Application/Control No.

10/658,361

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

OTSUKI, KOICHI

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	34,14,36 75,	4/12/2006	SWH
358	1.14,1.16	4/12/2006	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR